



XPS Depth of Info: 1-12 nm (0.001-0.012μ)
 EDS Depth of Info: 500-3,000 nm (0.5-3.0μ)

	Insulator Survey*	Atom%	Chemical States	Insulators	Info Depth (Z)	Smallest XY Size	Damage during analysis
EDS (SEM)	11-17 min	+/-15%	none	Need to coat w 20 nm Au	>500 nm (0.5μ)	800 nm (0.80 μ)	Possible (5-25 kV electrons)
XPS	8-15 min	+/-5%	many	Easy	1-12 nm (0.01μ)	30,000 nm (30.0 μ)	Rare (1.5 kV X-rays)

* Insulator Survey (5 min)